

**IV2Q20045BD – 2000V 45mΩ Gen2 SiC MOSFET chip**

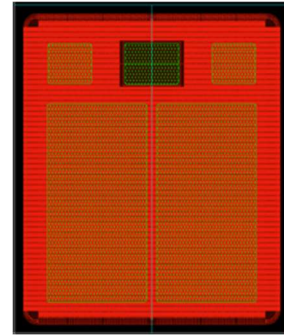
**Features**

- 2<sup>nd</sup> Generation SiC MOSFET Technology with +15~+18V gate drive
- High blocking voltage with low on-resistance
- High speed switching with low capacitance
- 175°C operating junction temperature capability
- Very fast and robust intrinsic body diode
- Kelvin gate input easing driver circuit design

**Applications**

- Solar boosters
- UPS power supplies
- Motor drivers
- Switch mode power supplies

**Chip Outline:**



Part Number	Die Size
IV2Q20045BD	Please contact your sales representative to get the detailed die information

**Absolute Maximum Ratings** ( $T_c=25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DS}$	Drain-Source voltage	2000	V	$V_{GS}=0V, I_D=100\mu A$	
$V_{GSmax}$ (Transient)	Maximum transient voltage	-10 to 23	V	Duty cycle<1%, and pulse width<200ns	
$V_{GSon}$	Recommended turn-on voltage	15 to 18	V		
$V_{GSoff}$	Recommended turn-off voltage	-5 to -2	V	Typical -3.5V	
$I_D$	Drain current (continuous)	62	A	$V_{GS}=18V, T_c=25^\circ\text{C}$	Fig. 23
$I_D$	Drain current (continuous)	46	A	$V_{GS}=18V, T_c=100^\circ\text{C}$	Fig. 23
$I_{DM}$	Drain current (pulsed)	155	A	Pulse width limited by SOA and dynamic $R_{\theta(j-c)}$	Fig. 25, 26
$I_{SM}$	Body diode current (pulsed)	155	A	Pulse width limited by SOA and dynamic $R_{\theta(j-c)}$	Fig. 25,26
$P_{TOT}$	Total power dissipation	500	W	$T_c=25^\circ\text{C}$	Fig. 24
$T_{stg}$	Storage temperature range	-55 to 175	$^\circ\text{C}$		
$T_J$	Operating junction temperature	-55 to 175	$^\circ\text{C}$		
$T_L$	Solder Temperature	260	$^\circ\text{C}$	wave soldering only allowed at leads, 1.6mm from case for 10 s	

**Note1:** Assumes  $R_{\theta(j-c)} < 0.3^\circ\text{C/W}$ .

**Note2:** All the electrical data and curve data please refer to datasheet for packaged device which part number is IV2Q20045T4.

**Electrical Characteristics** ( $T_c=25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Note
		Min.	Typ.	Max.			
$I_{DSS}$	Zero gate voltage drain current		1	10	$\mu\text{A}$	$V_{DS}=2000\text{V}, V_{GS}=0\text{V}$	
$I_{GSS}$	Gate leakage current			$\pm 100$	$\text{nA}$	$V_{DS}=0\text{V}, V_{GS}=-5\sim 20\text{V}$	
$V_{TH}$	Gate threshold voltage	1.8	2.8	4.5	$\text{V}$	$V_{GS}=V_{DS}, I_D=10\text{mA}$	Fig. 8, 9
			2.2			$V_{GS}=V_{DS}, I_D=10\text{mA}$ @ $T_J=175^\circ\text{C}$	
$R_{ON}$	Static drain-source on-resistance		43	56	$\text{m}\Omega$	$V_{GS}=18\text{V}, I_D=20\text{A}$ @ $T_J=25^\circ\text{C}$	Fig. 4, 5, 6, 7
			105		$\text{m}\Omega$	$V_{GS}=18\text{V}, I_D=20\text{A}$ @ $T_J=175^\circ\text{C}$	
			48		$\text{m}\Omega$	$V_{GS}=15\text{V}, I_D=20\text{A}$ @ $T_J=25^\circ\text{C}$	
			110		$\text{m}\Omega$	$V_{GS}=15\text{V}, I_D=20\text{A}$ @ $T_J=175^\circ\text{C}$	
$C_{iss}$	Input capacitance		3950		$\text{pF}$	$V_{DS}=1500\text{V}, V_{GS}=0\text{V},$ $f=1\text{MHz}, V_{AC}=25\text{mV}$	Fig. 16
$C_{oss}$	Output capacitance		110		$\text{pF}$		
$C_{rSS}$	Reverse transfer capacitance		13		$\text{pF}$		
$E_{oss}$	$C_{oss}$ stored energy		145		$\mu\text{J}$		Fig. 17
$Q_g$	Total gate charge		175		$\text{nC}$	$V_{DS}=1500\text{V}, I_D=20\text{A},$ $V_{GS}=-3$ to $18\text{V}$	Fig. 18
$Q_{gs}$	Gate-source charge		43		$\text{nC}$		
$Q_{gd}$	Gate-drain charge		63		$\text{nC}$		
$R_g$	Gate input resistance		1.5		$\Omega$	$f=1\text{MHz}$	
$E_{ON}$	Turn-on switching energy		870		$\mu\text{J}$	$V_{DS}=1200\text{V}, I_D=20\text{A},$ $V_{GS}=-3.5$ to $18\text{V},$ $R_{G(ext)}=3.3\Omega,$ $L=400\mu\text{H}, T_J=25^\circ\text{C}$	Fig. 19, 20
$E_{OFF}$	Turn-off switching energy		150		$\mu\text{J}$		
$t_{d(on)}$	Turn-on delay time		25		ns		
$t_r$	Rise time		24				
$t_{d(off)}$	Turn-off delay time		40				
$t_f$	Fall time		23				

**Reverse Diode Characteristics** ( $T_c=25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Note
		Min.	Typ.	Max.			
$V_{SD}$	Diode forward voltage		3.5		$\text{V}$	$I_{SD}=20\text{A}, V_{GS}=0\text{V}$	Fig. 10, 11, 12
			3.4		$\text{V}$	$I_{SD}=20\text{A}, V_{GS}=0\text{V},$ $T_J=175^\circ\text{C}$	
$t_{rr}$	Reverse recovery time		46		ns	$V_{GS}=-3.5\text{V}/+18\text{V},$	
$Q_{rr}$	Reverse recovery charge		550		$\text{nC}$	$I_{SD}=20\text{A}, V_R=1200\text{V},$	
$I_{RRM}$	Peak reverse recovery current		23		$\text{A}$	$R_{G(ext)}=5.1\Omega,$ $di/dt=3000\text{A}/\mu\text{s}$	

## Typical Performance (curves)

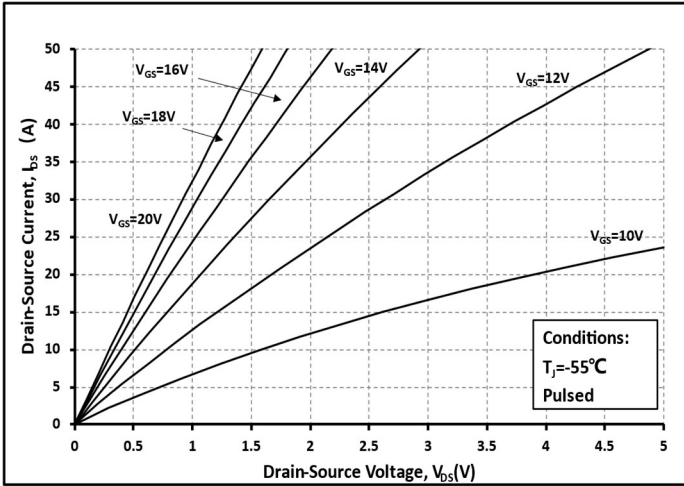


Fig. 1 Output Curve @  $T_j = -55^\circ\text{C}$

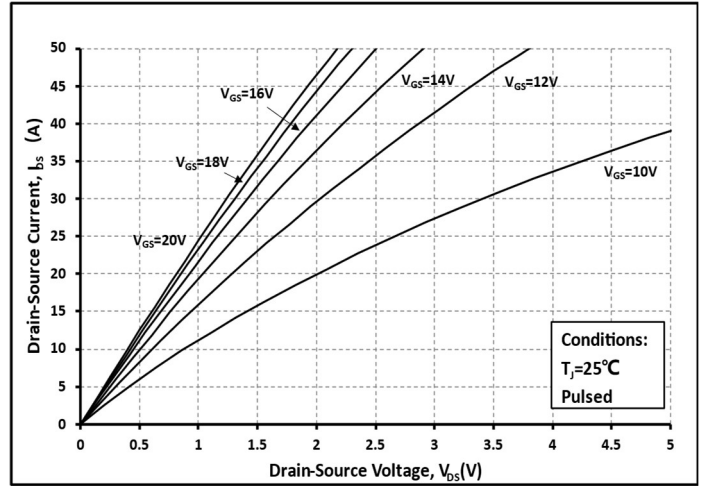


Fig. 2 Output Curve @  $T_j = 25^\circ\text{C}$

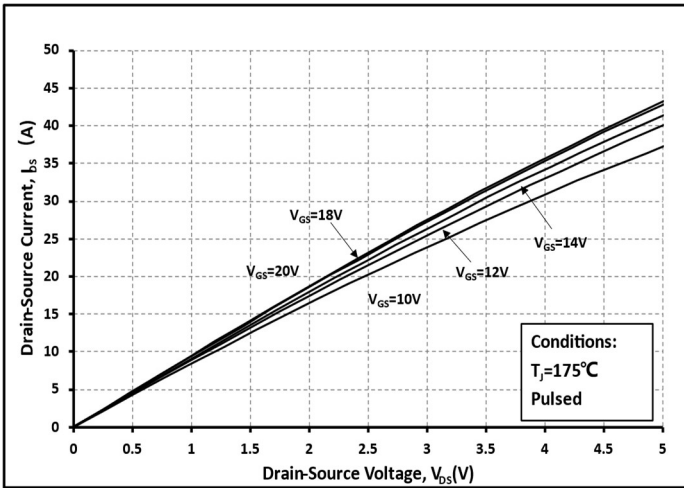


Fig. 3 Output Curve @  $T_j = 175^\circ\text{C}$

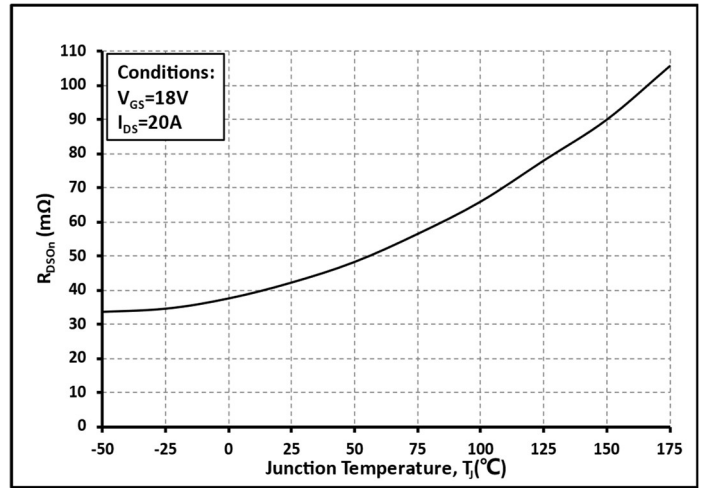


Fig. 4  $R_{\text{on}}$  vs. Temperature

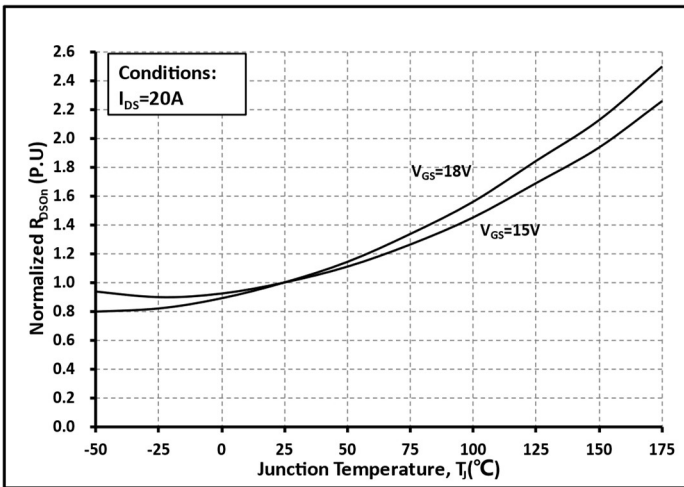


Fig. 5 Normalized  $R_{\text{on}}$  vs. Temperature

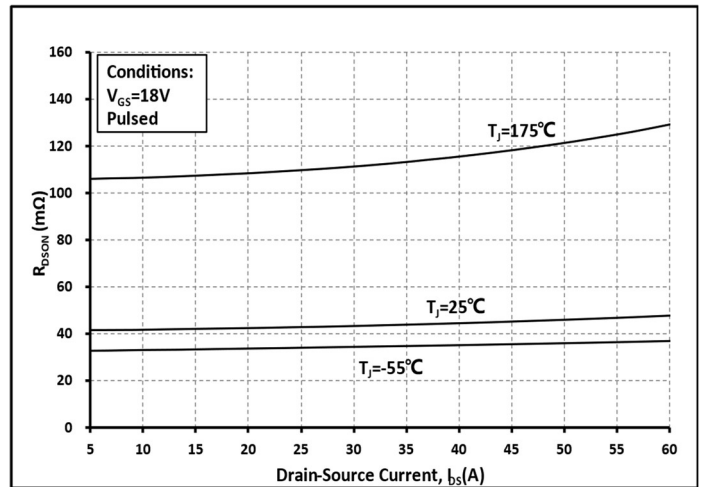


Fig. 6  $R_{\text{on}}$  vs.  $I_{\text{DS}}$  @ Various Temperature

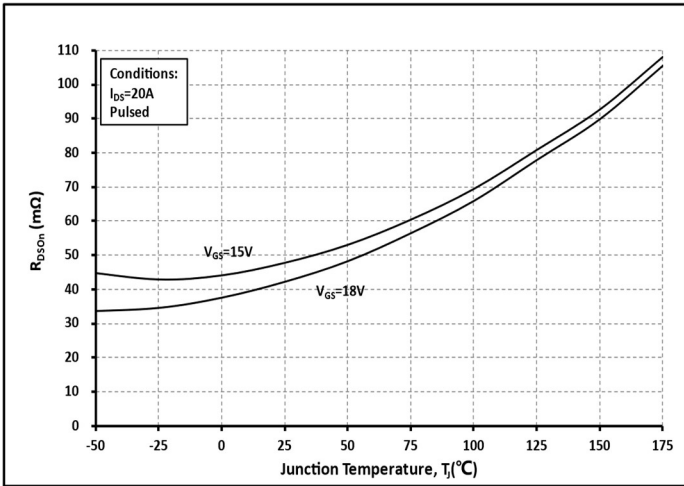


Fig. 7 Ron vs. Temperature @ Various  $V_{GS}$

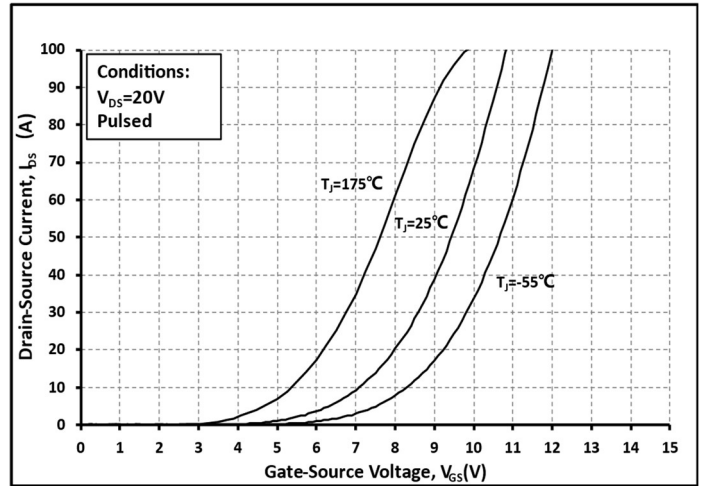


Fig. 8 Transfer Curves @ Various Temperature

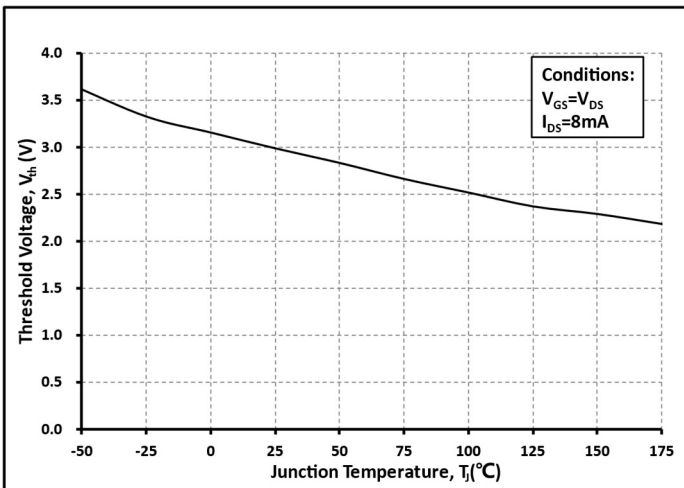


Fig. 9 Threshold Voltage vs. Temperature

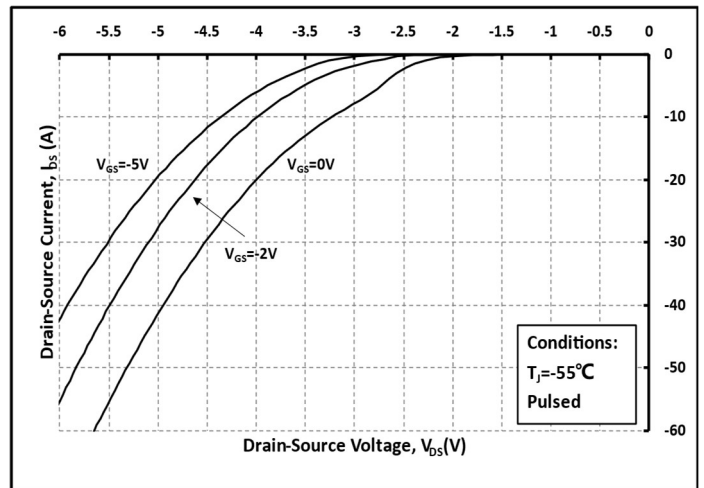


Fig. 10 Body Diode curves @  $T_j=-55^\circ C$

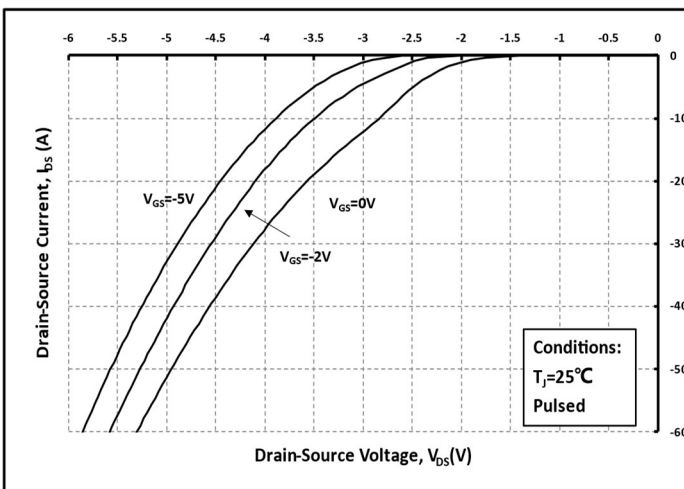


Fig. 11 Body Diode curves @  $T_j=25^\circ C$

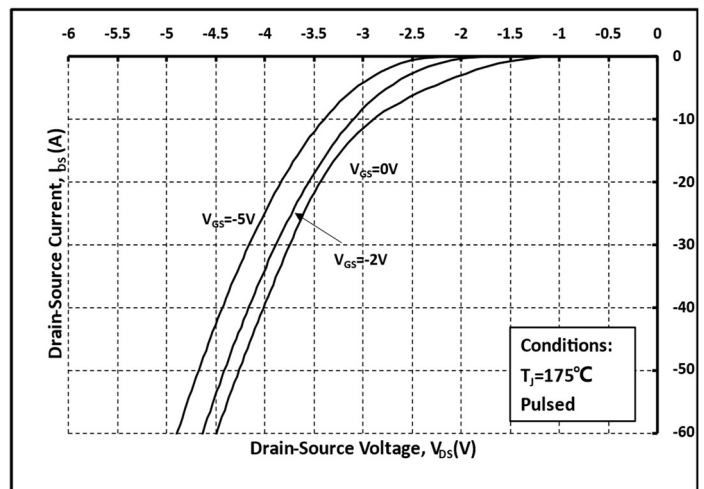


Fig. 12 Body Diode curves @  $T_j=175^\circ C$

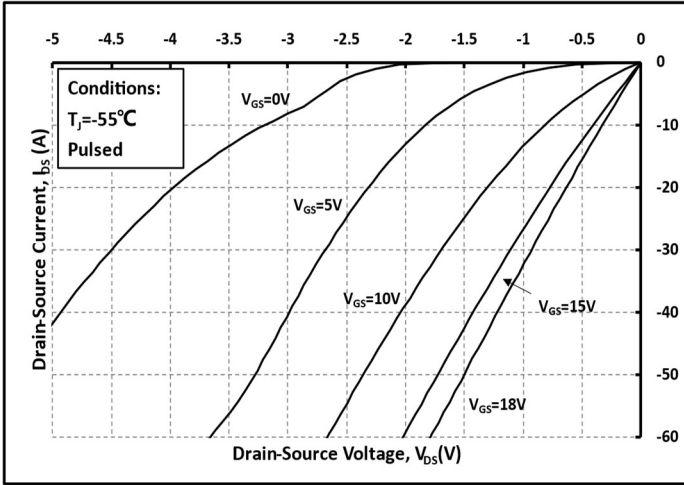


Fig. 13 3<sup>rd</sup> Quadrant curves @  $T_j = -55^\circ\text{C}$

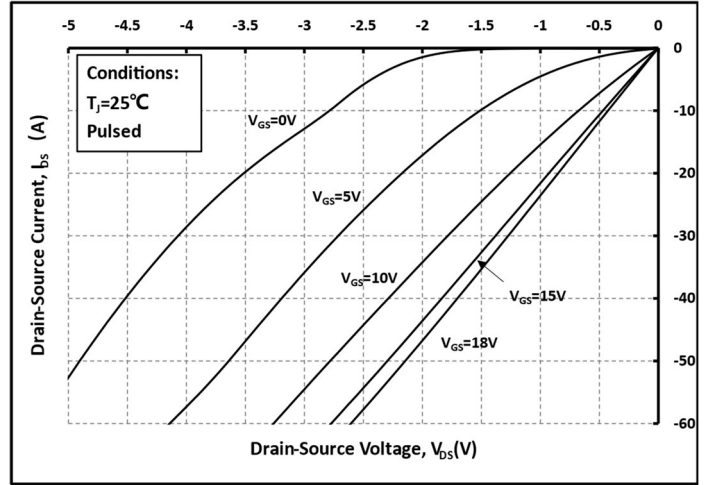


Fig. 14 3<sup>rd</sup> Quadrant curves @  $T_j = 25^\circ\text{C}$

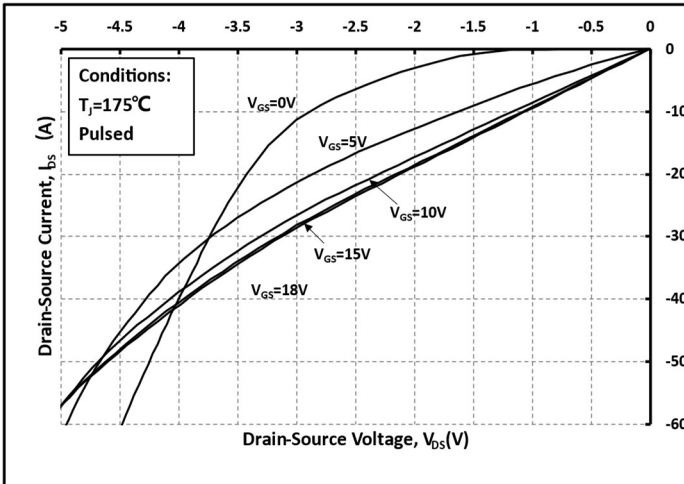


Fig. 15 3<sup>rd</sup> Quadrant curves @  $T_j = 175^\circ\text{C}$

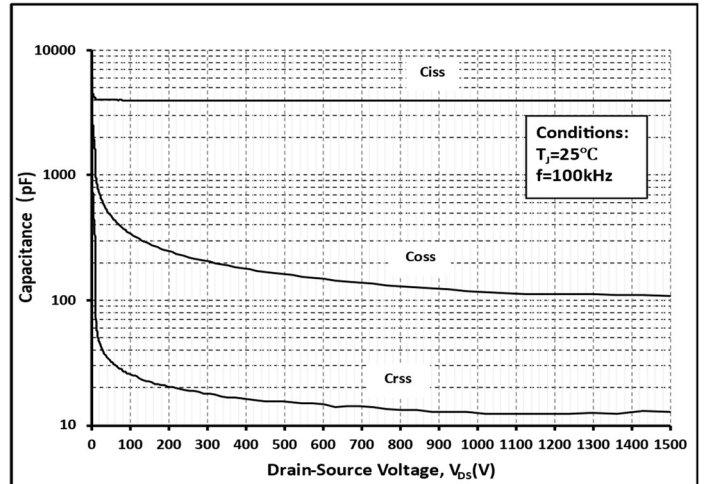


Fig. 16 Capacitance vs.  $V_{DS}$

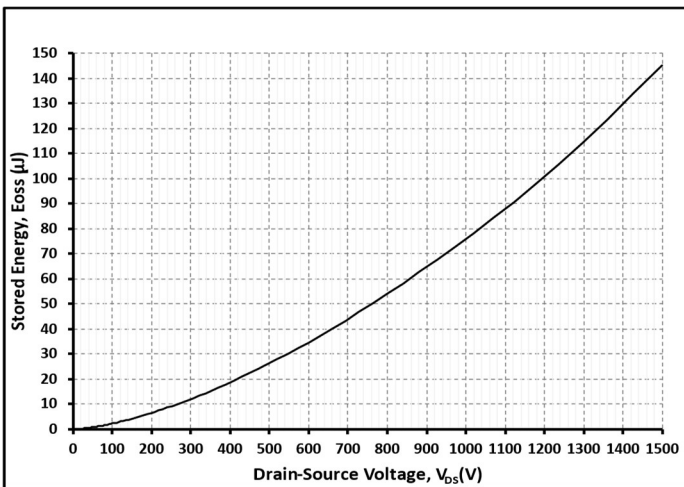


Fig. 17 Output Capacitor Stored Energy

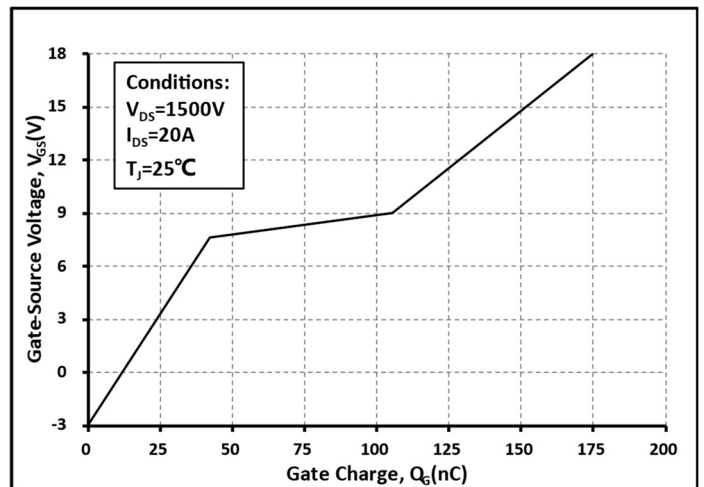


Fig. 18 Gate Charge Characteristics

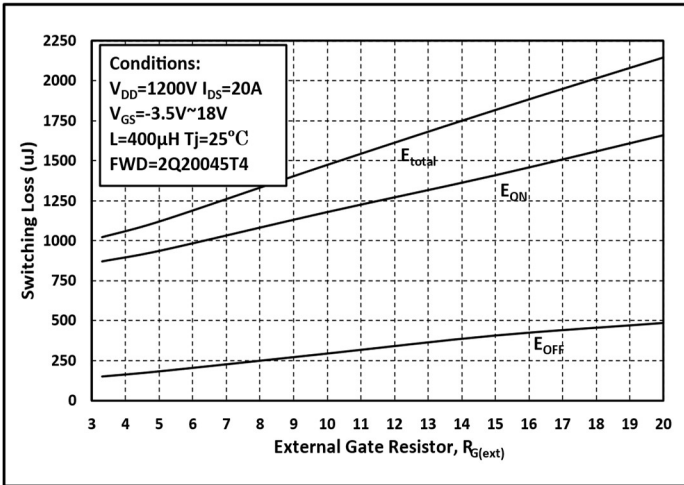


Fig. 19 Switching Energy vs.  $R_{G(ext)}$

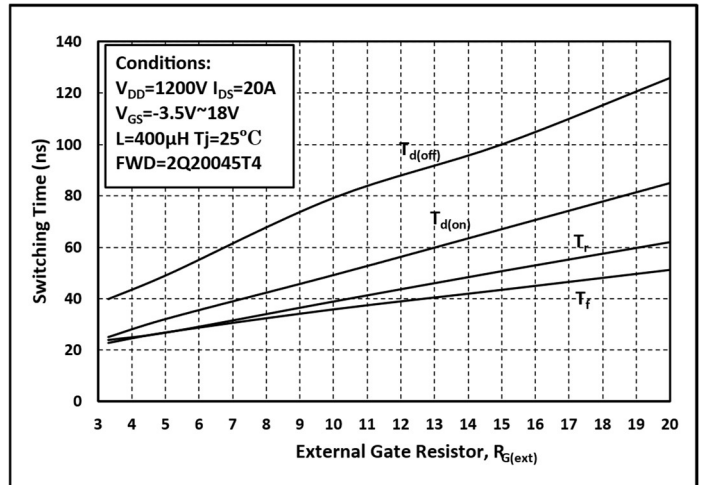


Fig. 20 Switching Times vs.  $R_{G(ext)}$

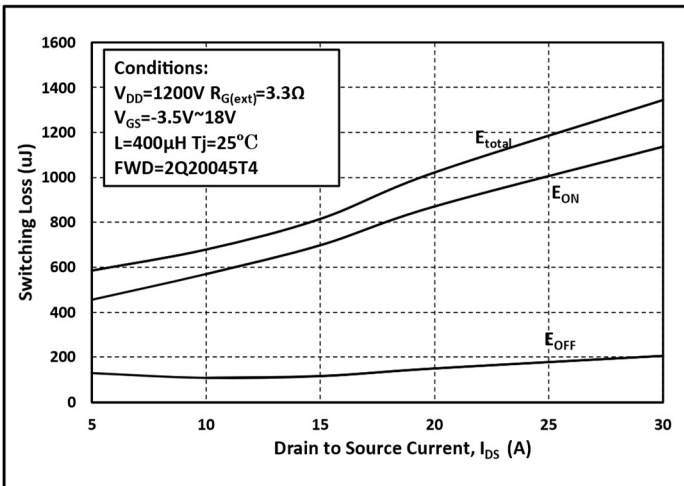


Fig. 21 Switching Energy vs.  $I_{DS}$

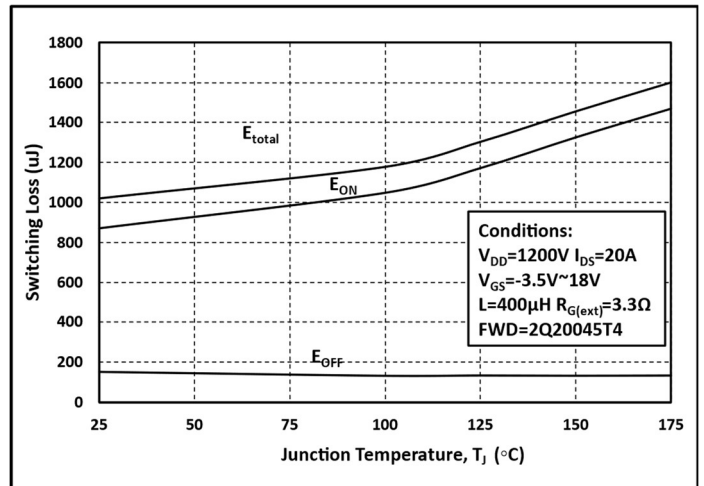


Fig. 22 Switching Energy vs. Temperature

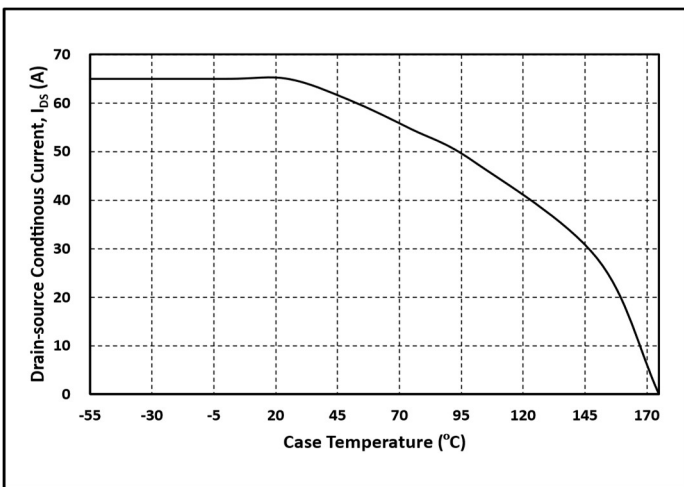


Fig. 23 Continuous Drain Current vs. Case Temperature

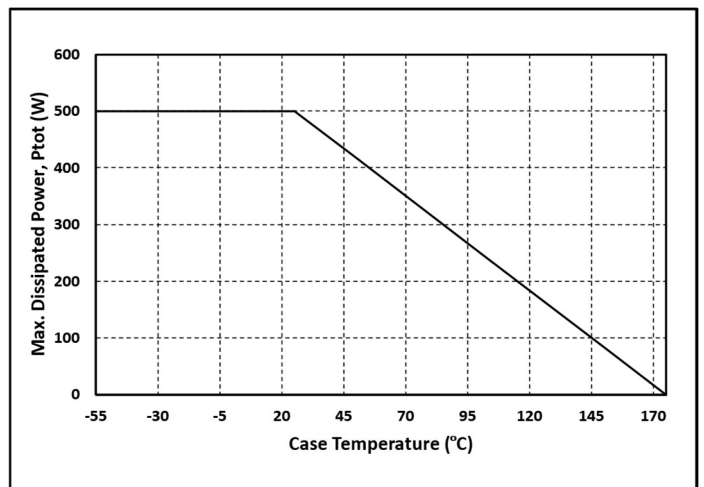


Fig. 24 Max. Power Dissipation Derating vs. Case Temperature

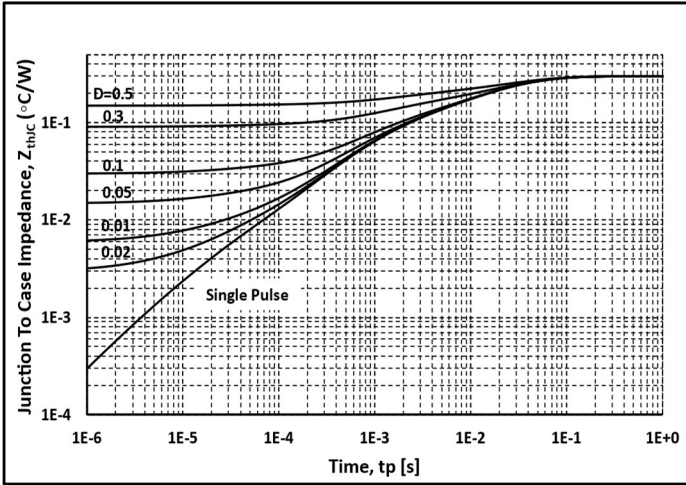


Fig. 25 Thermal impedance

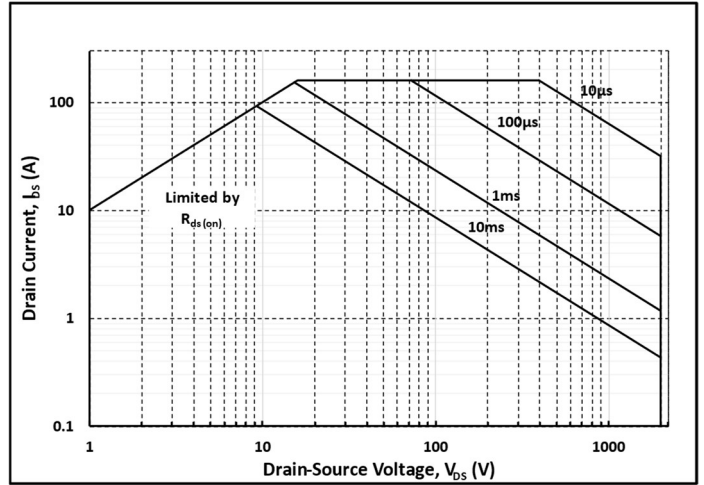


Fig. 26 Safe Operating Area

## Notes

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